

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

For rules and details of the IECQ visit www.iecq.org

IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 21.0004 Issue No.: 2 Status: Current

Supersedes: IECQ-L ULTW 21.0004 Issue 1 Issue Date: 2024/09/24 Org Issue: 2021/10/19

CB Reference No.: 50600039 ITL **Expiration: 2027/10/18**

Powertech Technology Inc. RA/CAL Lab

No. 15, Datong Rd., Hsinchu Industrial Park Hukou, Hsinchu 30352 Taiwan

The organization, facilities and procedures have been assessed by the IECQ Certification Body in accordance with IECQ 03-1 and IECQ 03-6 for issuance of this certificate and found to be in conformity with the applicable requirements of the IECQ Independent Testing Laboratory Assessment Program Requirements Scheme and in respect of ISO/IEC 17025:2017 for the testing of component product under the IECQ.

Scope:

Reliability test of semiconductor devices and the calibration of thermometer.

See attached Schedule.

-- Attached Schedule: IECQ-L_ULTW_50600039 ITL, 09-24-24.pdf --

Approved by Certification Body (CB): DQS Group - DQS Taiwan Inc.

8F, 23, Yuan Huan West Road, Feng Yuan Dist., Taichung City Taiwan

Authorized person:

Rock Chang







The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.

This Certificate of Conformity may be suspended or withdrawn in accordance with the Rules of Procedure of the IECQ System and its Schemes.

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This certificate is not transferable and remains the property of the issuing IECQ CB.

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IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components, Assemblies, Related Materials and Processes

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Schedule of Scope to Certificate of Conformity Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 21.0004
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Appendix-1 (50600039 ITL) Schedule of Scope to Certificate of Approval

Description test	Standard
Pre condition	J-STD-020
Temperature Cycling (TCT)	JESD22-A104
High Temperature Storage Life (HTSL)	JESD22-A103
Highly Accelerated Temperature and Humidity Stress Test (HAST)	JESD22-A110
Accelerated Moisture Resistance -Unbiased Autoclave (AC)	JESD22-A102
Accelerated Moisture Resistance - Unbiased HAST (uHAST)	JESD22-A118
Steady-State Temperature-Humidity Bias Life Test (THB)	JESD22-A101
Temperature-Humidity Life Test (TH)	JESD22-A101

Description test	Range	Standard
Temperature	0°℃~500°℃	EURAMET_cg-11

Technical Reviewer of DQS:	 	Date: 9/24/2024	

Twe Alexander

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